

UNCONTROLLED DOCUMENT

SC:0.25

PART NUMBER

REV.

SSD-LX014E880SXX

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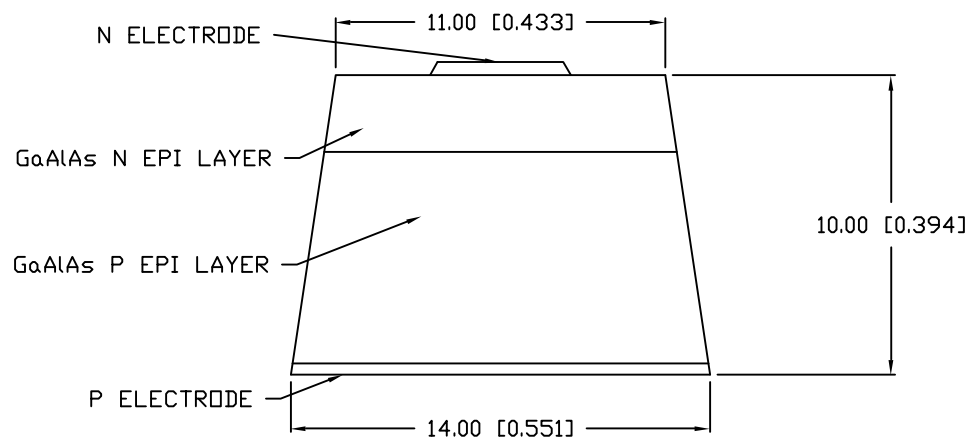
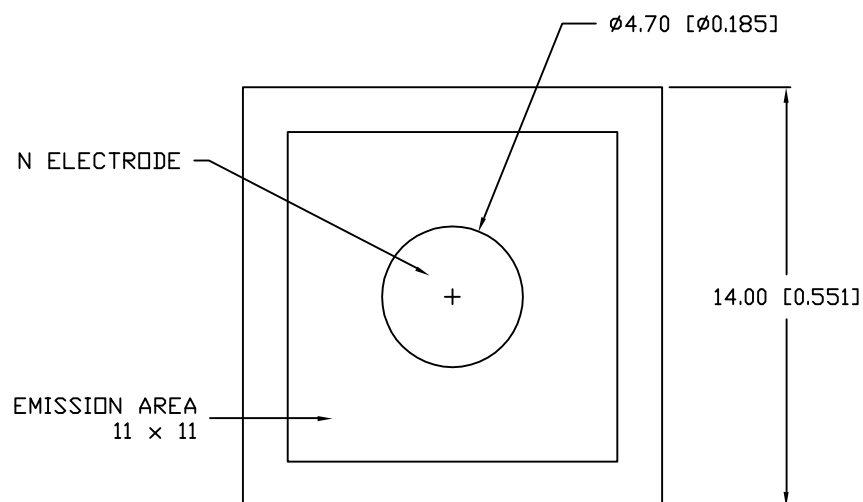
REV. E.C.N. NUMBER AND REVISION COMMENTS

DATE

A E.C.N. #10BRDR.

10.15.97

UNDER REVISION



ELECTRO-OPTICAL CHARACTERISTICS:

PARAMETER	SYMBOL		TEST COND	MIN	TYP	MAX	UNIT
FORWARD VOLTAGE	V _{f1}		I _f =10μA		1.30	1.50	V
	V _{f2}		I _f =20mA		1.70		V
REVERSE CURRENT	I _r		V _r =5V		10		μA
PEAK WAVELENGTH	λ _p		I _f =20mA		880		nm
SPECTRA HALF-WIDTH	Δλ		I _f =20mA		70		nm
LUMINOUS INTENSITY ⁽¹⁾	I _v	A4	I _f =20mA	50	I _v (ave.) ⁽²⁾ ≥60		mcd
		A5		60	I _v (ave.) ⁽²⁾ ≥75		
		A6		75	I _v (ave.) ⁽²⁾ ≥100		

(1) $I_v(ave.)$ is the average luminous intensity of overall qualified chips from individual epiwafer.

NOTE:

UNITS: mil

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*UNLESS OTHERWISE SPECIFIED TOLERANCES PER DECIMAL PRECISION ARE: X=±1 (±0.039), X.X=±0.5 (±0.020), X.XX=±0.25 (±0.010), X.XXX=±0.127 (±0.005). LEAD SIZE=±0.05 (±0.002), LEAD LENGTH=±0.75 (±0.030). MIN.=+DECIMAL PRECISION -0.00 MAX.=+0.00 -DECIMAL PRECISION

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INFRARED EMITTING DIODE CHIP.

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RELIABILITY NOTE

OUR MANY YEARS OF EXPERIENCE DATA ACCUMULATION INDICATE THAT SOLDER HEAT IS A MAJOR CAUSE OF EARLY AND FUTURE FAILURE. PLEASE PAY ATTENTION TO YOUR SOLDERING PROCESS.



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